

Notice of References Cited

Application/Control No.

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Applicant(s)/Patent Under

Reexamination

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Examiner

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Art Unit

3641

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U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-694,896 A	03-1902	SCOTT et al.	102/438
*	B US-3,899,975 A	08-1975	Lawrence, John Charles	102/505
*	C US-4,708,064 A	11-1987	Bisping et al.	102/517
*	D US-6,431,076 B1	08-2002	ODwyer, James Michael	102/525
*	E US-6,510,643 B2	01-2003	ODwyer, James Michael	42/84
*	F US-6,543,174 B2	04-2003	ODwyer, James Michael	42/76.01
*	G US-6,662,726 B1	12-2003	Steiner, Edwin G.	102/521
*	H US-2004/0231219 A1	11-2004	ODwyer, James Michael	042/084
*	I US-6,862,996 B2	03-2005	Key, Mark	102/517
*	J US-2007/0028794 A1	02-2007	ODwyer, James Michael	102/520
*	K US-7,194,943 B2	03-2007	ODwyer, Sean Patrick	89/28.05
*	L US-2007/0056460 A1	03-2007	ODwyer et al.	102/374
M	US-			

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
W	
X	

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